

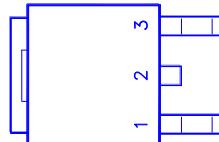
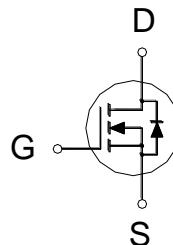
NIKO-SEM
**N-Channel Enhancement Mode
Field Effect Transistor**
PD600BA

TO-252

Halogen-Free & Lead-Free

**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
30V	9.5mΩ	42A


 1. GATE
 2. DRAIN
 3. SOURCE
ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

100% RG Test , 100% UIL Test

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		V_{DS}	30	V
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current ²	$T_C = 25^\circ\text{C}$	I_D	42	A
	$T_C = 100^\circ\text{C}$		26	
Pulsed Drain Current ¹		I_{DM}	120	A
Avalanche Current		I_{AS}	20	
Avalanche Energy	$L = 0.1\text{mH}$	E_{AS}	20	mJ
Power Dissipation	$T_C = 25^\circ\text{C}$	P_D	32	W
	$T_C = 100^\circ\text{C}$		13	
Junction & Storage Temperature Range		T_J, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		3.8	°C / W
Junction-to-Ambient	$R_{\theta JA}$		62.5	

¹Pulse width limited by maximum junction temperature.²Package limitation current is 28A**ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	30			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1.3	1.75	2.3	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\text{V}, V_{GS} = \pm 20\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 24\text{V}, V_{GS} = 0\text{V}$			1	μA
		$V_{DS} = 20\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$			10	
Drain-Source On-State Resistance ¹	$R_{DS(\text{ON})}$	$V_{GS} = 4.5\text{V}, I_D = 15\text{A}$		9.6	13.5	$\text{m}\Omega$
		$V_{GS} = 10\text{V}, I_D = 20\text{A}$		7.3	9.5	

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Forward Transconductance ¹	g_{fs}	$V_{DS} = 5V, I_D = 20A$	63		S
DYNAMIC					
Input Capacitance ⁴	C_{iss}	$V_{GS} = 0V, V_{DS} = 15V, f = 1MHz$	493	617	740
Output Capacitance ⁴	C_{oss}		96	120	144
Reverse Transfer Capacitance ⁴	C_{rss}		50	84	118
Gate Resistance	R_g	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$	1.3	2.5	3.8
Total Gate Charge ^{2,4}	Q_g	$V_{GS} = 10V, V_{DS} = 15V, I_D = 20A$	11	14	17
Gate-Source Charge ^{2,4}	Q_{gs}		1.2	1.5	1.8
Gate-Drain Charge ^{2,4}	Q_{gd}		2.2	3.7	5.2
Turn-On Delay Time ²	$t_{d(on)}$	$V_{DS} = 15V$ $I_D \geq 20A, V_{GS} = 10V, R_{GEN} = 6\Omega$		17	
Rise Time ²	t_r			41	
Turn-Off Delay Time ²	$t_{d(off)}$			55	
Fall Time ²	t_f			30	
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)					
Continuous Current ³	I_S			29	A
Forward Voltage ¹	V_{SD}	$I_F = 20A, V_{GS} = 0V$		1.1	V
Reverse Recovery Time ⁴	t_{rr}	$I_F = 20A, dI_F/dt = 100A/\mu s$	5	10	18
Reverse Recovery Charge ⁴	Q_{rr}		1.5	3	4.5

¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

³Package limitation current is 28A

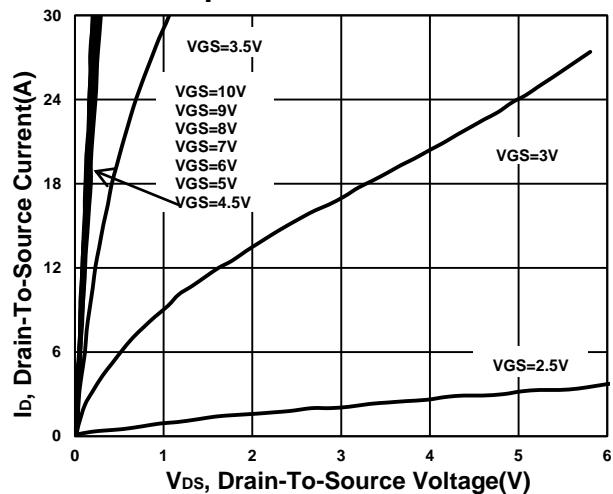
⁴Guaranteed by design, not subject to production testing.

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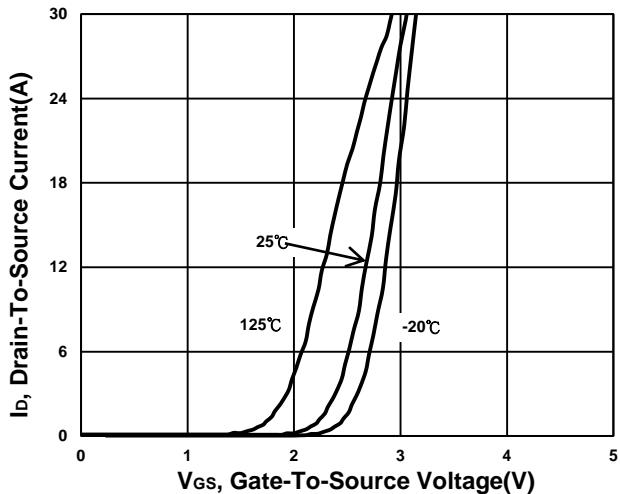
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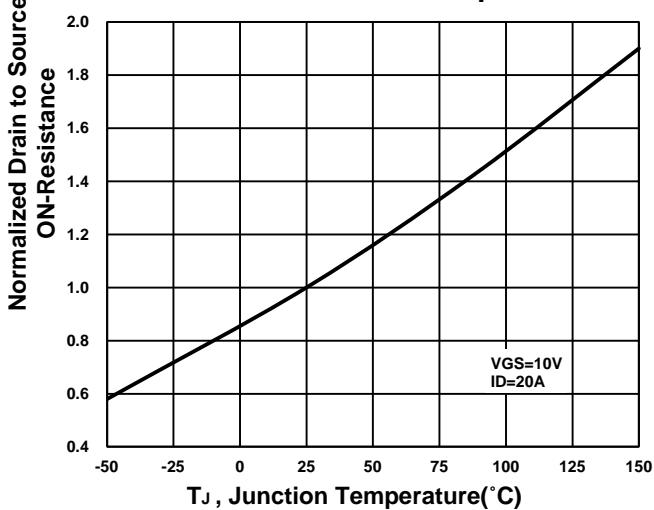
Output Characteristics



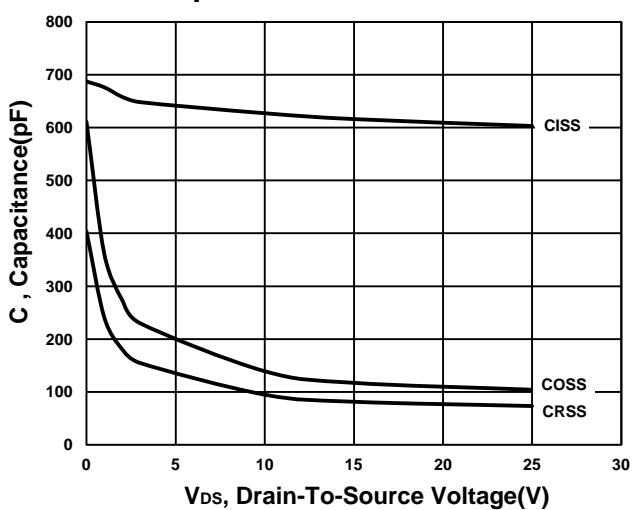
Transfer Characteristics



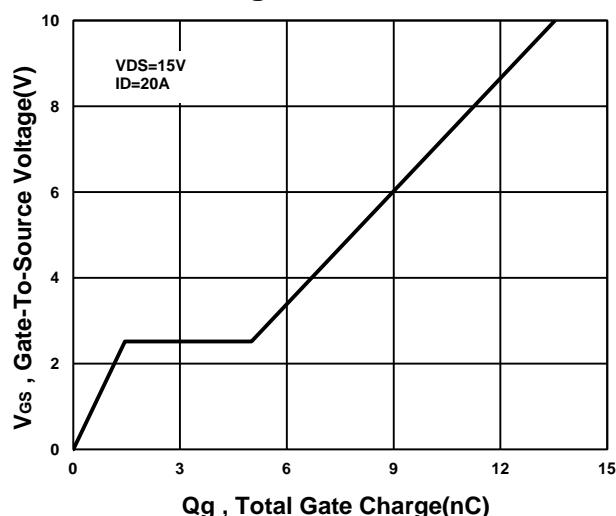
On-Resistance VS Temperature



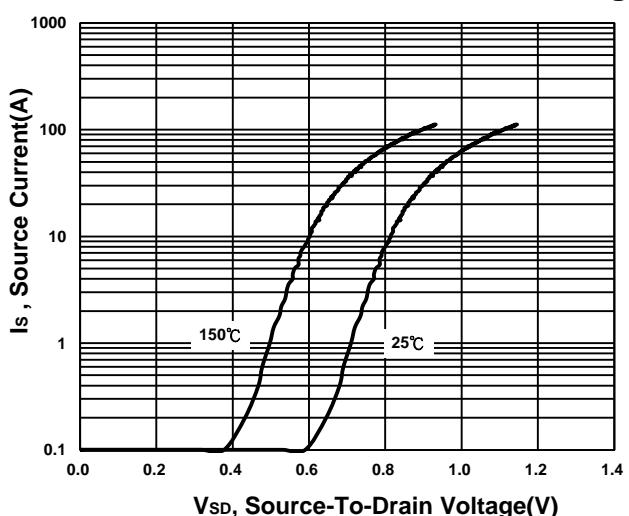
Capacitance Characteristic



Gate charge Characteristics



Source-Drain Diode Forward Voltage

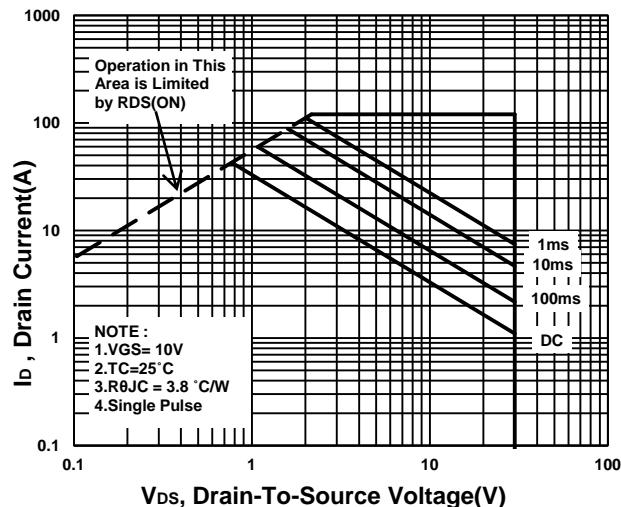


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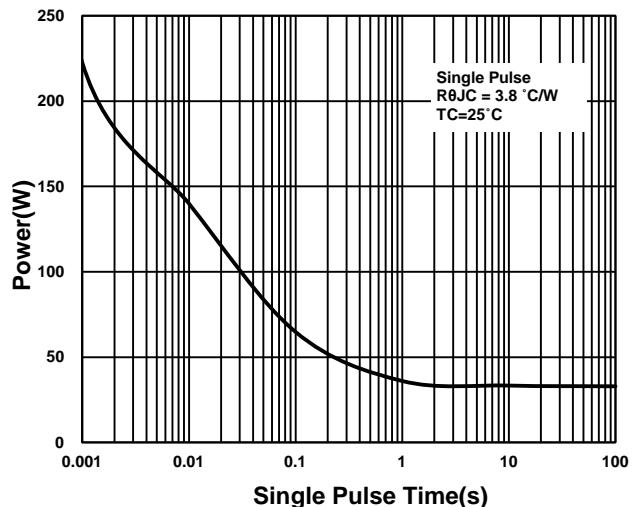
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Safe Operating Area



Single Pulse Maximum Power Dissipation



Transient Thermal Response Curve

